



**SKiM® 4**

## IGBT Modules

### SKiM 300GD126D

#### Preliminary Data

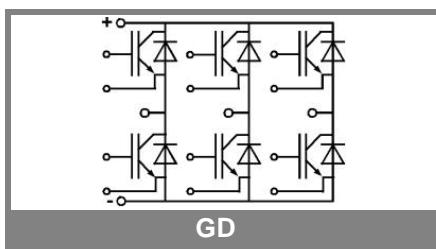
#### Features

- Trench gate IGBT with field stop layer
- Low inductance case
- Fast & soft inverse CAL diode
- Isolated by  $\text{Al}_2\text{O}_3$  DCB (Direct Copper Bonded) ceramic plate
- Pressure contact technology for thermal contacts
- Spring contact system to attach driver PCB to the control terminals
- Integrated temperature sensor

#### Typical Applications

- Switched mode power supplies
- Three phase inverters for AC motor speed control
- Switching (not for linear use)

Absolute Maximum Ratings		$T_c = 25^\circ\text{C}$ , unless otherwise specified		
Symbol	Conditions	Values		Units
<b>IGBT</b>				
$V_{CES}$		1200		V
$I_C$	$T_s = 25 \text{ (70)}^\circ\text{C}$	265 (200)		A
$I_{CRM}$	$t_p = 1 \text{ ms}$	600		A
$V_{GES}$		$\pm 20$		V
$T_j (T_{stg})$		- 40 ... + 150 (125)		°C
$T_{cop}$	max. case operating temperature	125		°C
$V_{isol}$	AC, 1 min.	2500		V
<b>Inverse diode</b>				
$I_F$	$T_s = 25 \text{ (70)}^\circ\text{C}$	260 (200)		A
$I_{FRM}$	$t_p = 1 \text{ ms}$	520		A
$I_{FSM}$	$t_p = 10 \text{ ms}; \sin.; T_j = 150^\circ\text{C}$	2200		A
Characteristics		$T_c = 25^\circ\text{C}$ , unless otherwise specified		
Symbol	Conditions	min.	typ.	max.
<b>IGBT</b>				
$V_{GE(th)}$	$V_{GE} = V_{CE}; I_C = 12 \text{ mA}$	4,95	5,8	6,55
$I_{CES}$	$V_{GE} = 0; V_{CE} = V_{CES}; T_j = 25^\circ\text{C}$	0,2	0,6	mA
$V_{CEO}$	$T_j = 25 \text{ (125)}^\circ\text{C}$		1 (0,9)	1,2 (1,1)
$r_{CE}$	$T_j = 25 \text{ (125)}^\circ\text{C}$		2,3 (3,4)	3,2 (4,5)
$V_{CEsat}$	$I_{Cnom} = 300 \text{ A}; V_{GE} = 15 \text{ V}, T_j = 25 \text{ (125)}^\circ\text{C}$ on chip level		1,7 (2)	2,15 (2,45)
$C_{ies}$	$V_{GE} = 0; V_{CE} = 25 \text{ V}; f = 1 \text{ MHz}$	23		nF
$C_{oes}$	$V_{GE} = 0; V_{CE} = 25 \text{ V}; f = 1 \text{ MHz}$	1,6		nF
$C_{res}$	$V_{GE} = 0; V_{CE} = 25 \text{ V}; f = 1 \text{ MHz}$	1,6		nF
$L_{CE}$				15 nH
$R_{CC' + EE'}$	resistance, terminal-chip $T_c = 25 \text{ (125)}^\circ\text{C}$		1,35 (1,75)	mΩ
$t_{d(on)}$	$V_{CC} = 600 \text{ V}$	320		ns
$t_f$	$I_{Cnom} = 300 \text{ A}$	75		ns
$t_{d(off)}$	$R_{Gon} = R_{Goff} = 4,7 \Omega$	800		ns
$t_f$	$T_j = 125^\circ\text{C}$	130		ns
$E_{on} (E_{off})$	$V_{GE} \pm 15 \text{ V}$		28 (47)	mJ
$E_{on} (E_{off})$	with SKHI 64; $T_j = 125^\circ\text{C}$			
	$V_{CC} = 600 \text{ V}; I_C = 300 \text{ A}$			mJ
<b>Inverse diode</b>				
$V_F = V_{EC}$	$I_{Fnom} = 200 \text{ A}; V_{GE} = 0 \text{ V}; T_j = 25 \text{ (125)}^\circ\text{C}$	2 (1,8)	2,55 (2,3)	V
$V_{TO}$	$T_j = 25 \text{ (125)}^\circ\text{C}$	1,1	1,45 (1,25)	V
$r_T$	$T_j = 25 \text{ (125)}^\circ\text{C}$	4,5	5,3 (5,3)	mΩ
$I_{RRM}$	$I_F = 300 \text{ A}; T_j = 125^\circ\text{C}$			A
$Q_{fr}$	$V_{GE} = 0 \text{ V} \frac{di}{dt} = A/\mu\text{s}$			μC
$E_{rr}$	$R_{Gon} = R_{Goff} = 4,7 \Omega$			mJ
<b>Thermal characteristics</b>				
$R_{th(j-s)}$	per IGBT		0,2	kW
$R_{th(j-s)}$	per FWD		0,285	kW
<b>Temperature Sensor</b>				
$R_{TS}$	$T = 25 \text{ (100)}^\circ\text{C}$		1 (1,67)	kΩ
tolerance	$T = 25 \text{ (100)}^\circ\text{C}$		3 (2)	%
<b>Mechanical data</b>				
$M_1$	to heatsink (M5)	2	3	Nm
$M_2$	for terminals (M6)	4	5	Nm
$w$			310	g



# SKiM 300GD126D

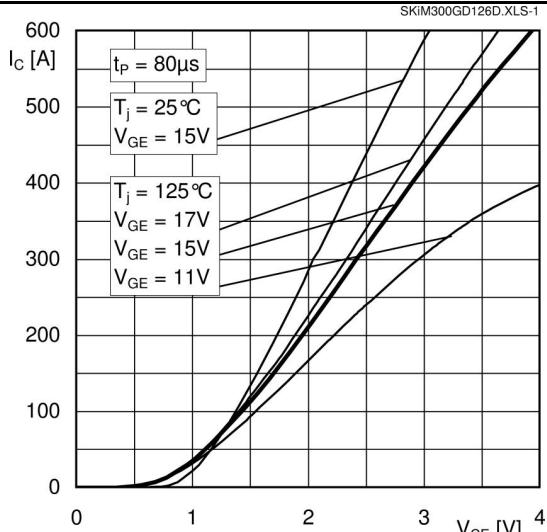


Fig. 1 Output characteristic, inclusive  $R_{CC} + EE$

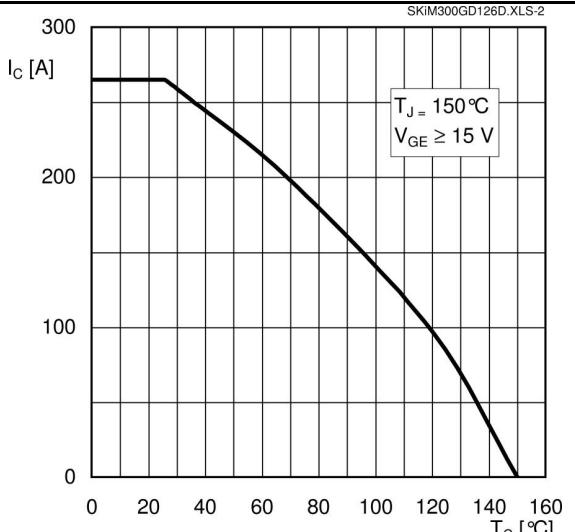


Fig. 2 Rated current vs. temperature  $I_C = f(T_C)$

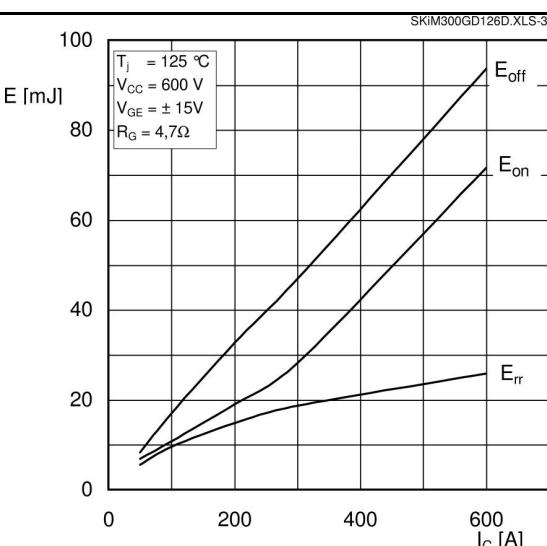


Fig. 3 Turn-on /-off energy =  $f(I_C)$

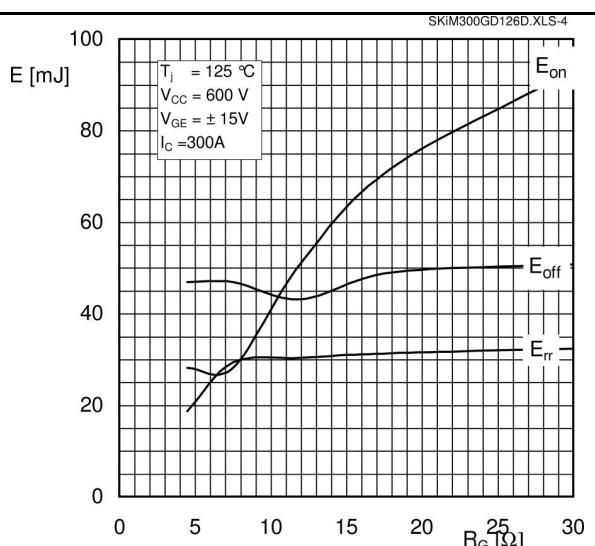


Fig. 4 Turn-on /-off energy =  $f(R_G)$

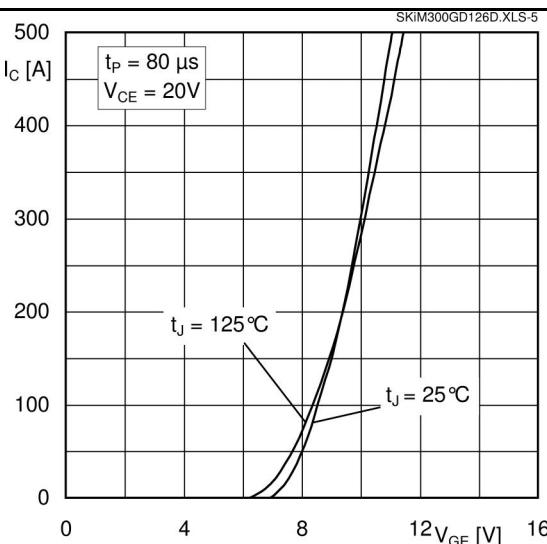


Fig. 5 Transfer characteristic

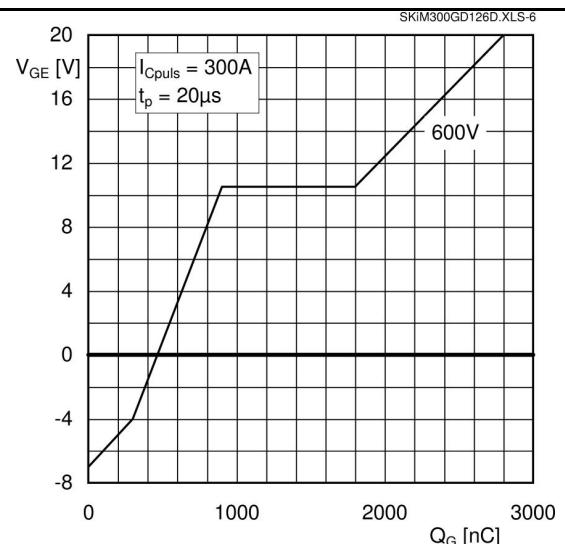


Fig. 6 Gate charge characteristic

# SKiM 300GD126D

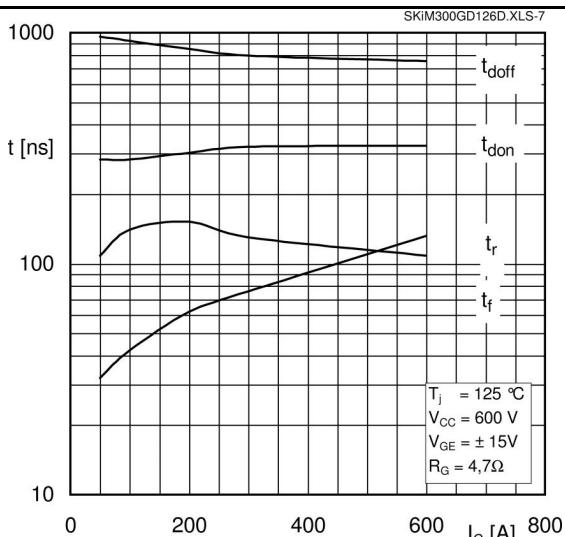


Fig. 7 Switching times vs.  $I_C$

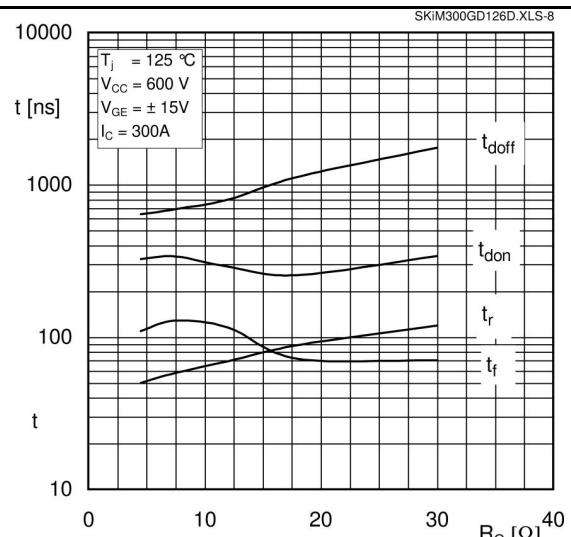


Fig. 8 Switching times vs. gate resistor  $R_G$

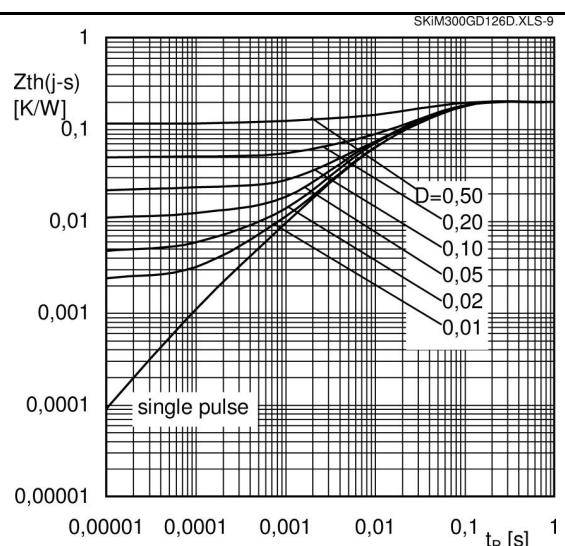


Fig. 9 Transient thermal impedance of  
IGBT  $Z_{thJC} = f(t_p)$ ;  $D = t_p/t_c = t_p * f$

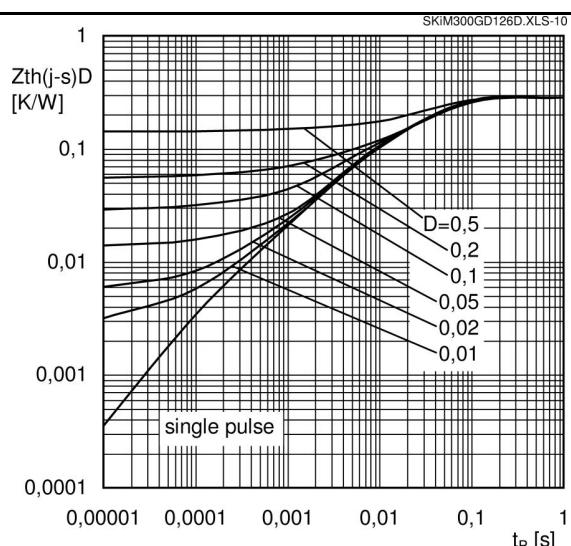


Fig. 10 Transient thermal impedance of inverse diodes  
IGBT  $Z_{thJC} = f(t_p)$ ;  $D = t_p/t_c = t_p * f$

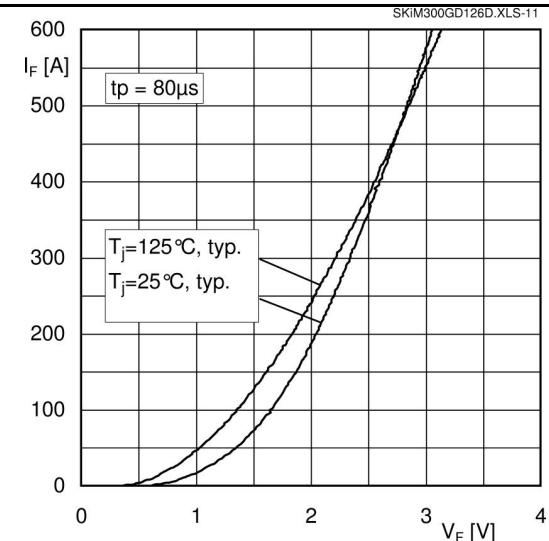
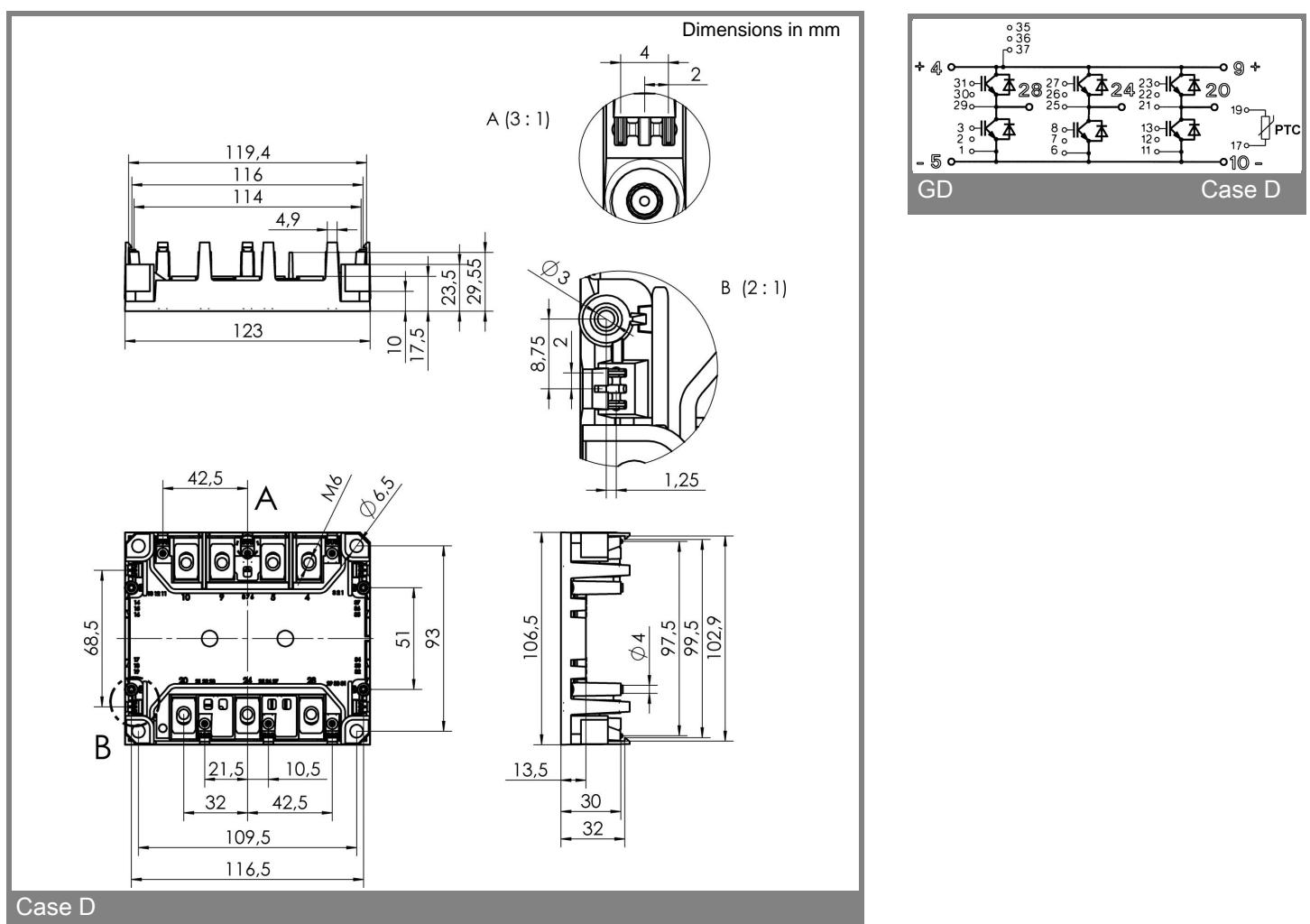


Fig. 11 CAL diode forward characteristic, incl.  $R_{CC+EE'}$



This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.